ieee home | search ieee | shop | web account | contact ieee



Membership	Publications/Services	Standards	Conferences	Careers/Jobs
122	E Xologe		United States Pi	Welcome stent and Traden

Welcome United States Patent and Trademark Office



Help FAQ Terms IEEE Peer Review

**Quick Links** 

Se Se

# Valorate to IEEE Valors

- C> Home
- (\*)- What Can | Access?
- O- Log-out

# 

- Journals & Magazines
- > Conference Proceedings |
- ( ) Standards

## Search

- 🔾 By Author
- (")~ Basic
- ( )~ Advanced

# 

- O- Join IEEE
- Establish IEEE Web Account
- O- Access the iEEE Member Digital Library

Your search matched 4 of 1015452 documents.

A maximum of 500 results are displayed, 15 to a page, sorted by Relevance **Descending** order.

#### Refine This Search:

You may refine your search by editing the current search expression or enterior new one in the text box.

(watermark\* or hid\* or embed\* or steganograph\*) <para

Search

Check to search within this result set

#### Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

## 1 A general family of multivariable digital lattice filters

Vaidyanathan, P.; Mitra, S.;

Circuits and Systems, IEEE Transactions on , Volume: 32 , Issue: 12 , Dec 19 Pages:1234 - 1245

[Abstract] [PDF Full-Text (1240 KB)] **IEEE JNL** 

#### 2 Association and content-based retrieval

Djeraba, C.;

Knowledge and Data Engineering, IEEE Transactions on , Volume: 15, Issue: 1 , Jan.-Feb. 2003

Pages:118 - 135

[Abstract] [PDF Full-Text (6991 KB)] **IEEE JNL** 

# 3 Object localization in 2D images based on Kohonen's self-organizati feature maps

Yuan, C.; Niemann, H.;

Neural Networks, 1999. IJCNN '99. International Joint Conference on , Volum 5 , 10-16 July 1999

Pages:3134 - 3137 vol.5

[Abstract] [PDF Full-Text (376 KB)] **IEEE CNF** 

#### 4 Analysis of real-time embedded systems for co-design

Benders, L.P.M.;

Rapid System Prototyping, 1995. Proceedings., Sixth IEEE International Work on , 7-9 June 1995

Pages:26 - 32

#### [PDF Full-Text (592 KB)] [Abstract] **IEEE CNF**

iteme | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ | Terms | Seck to Top

Copyright © 2004 IEEE — All rights reserved